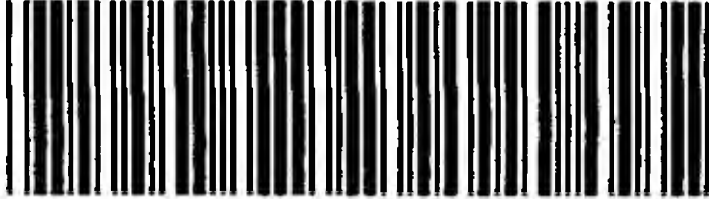


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,959	HENG ET AL.	
	Examiner	Art Unit	
	Phallaka Kik	2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	3,2,9,10	12/26/2006	PK
Above	updated	4/9/2007	PK
Above	updated	9/29/2007	PK
Above	updated	11/5/2007	PK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	3,2,9,10	11/5/2007	PK
--USPGPUB (see attached)		11/5/2007	PK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB New search Class/sub searched: 716/1-18 (see attached)	12/26/2006	PK
Above updated (see attached)	4/9/2007	PK
Above updated (see attached)_	9/29/2007	PK
Above updated (see attached)	11/5/2007	PK
IEE/IEEE Xplore new search (see attached)	12/26/2006	PK
--EPO, JPO, IBM TDB, Derwent new search (see attached)	12/26/2006	PK